

## **APPENDIX**

Changes to Claims: Claims 15 and 16 are added. The following are marked-up versions of the amended claims: (Amended) A semiconductor device, comprising: 1. a silicon substrate and a metal-oxide-semiconductor field-effect transistor formed on said siliconsubstrate, wherein a gate electrode of said transistor comprises a germanium filmthat includes: a gate insulation film and a gate electrode on the gate insulation film, the gate electrode including a germanium film on the gate insulation film. 7. (Amended) A semiconductor device, comprising: an n-channel metal-oxide-semiconductor field-effect transistor; and a p-channel metal-oxide-semiconductor field-effect transistor, wherein a gate electrode of each of said transistors comprises any one of a single-crystalline germanium film, a polycrystalline germanium film or an amorphous germanium film in which p type impurities are dopedat least one of the n-channel metaloxide-semiconductor field-effect transistor and the p-channel metal-oxide-semiconductor field-effect transistor including: a gate insulation film and a gate electrode on the gate insulation film, the gate electrode including a germanium film on the gate insulation film.